

Abstracts

Note on Reflectometer for Measuring the Magneto-Microwave Kerr Effect in Semiconductors (Correspondence)

R.J. Vernon. "Note on Reflectometer for Measuring the Magneto-Microwave Kerr Effect in Semiconductors (Correspondence)." 1968 Transactions on Microwave Theory and Techniques 16.4 (Apr. 1968 [T-MTT]): 262-262.

Hauge and Champlin recently described an interesting new system which they used to measure the magneto-microwave Kerr effect semiconductors. In response to their discussion of this system certain features should be pointed out concerning another reflectometer used earlier for a similar purpose by Brodwin and Vernon.

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